PC4SF21YVZ Series

PC4SF21YVZ Series

■ Features

SHARP

- 1. High repetitive peak OFF-state voltage (V_{DRM}):800V
- 2. Low zero-cross voltage (VOXIMAX.]=20V)
- 3. Isolation voltage between input and output (V_{iso (rms)}:5kV)
- 4. Internal isolation distance (0.4mm or more)
- 5. Recognized by UL (File No. E64380)

Approved by CSA (File No. CA95323)

Approved by VDE (VDE0884, File No.127413)

Approved by BSI (BS415, File No.6690,

BS7002, File No.7421)

Approved by SEMKO (File No.0033029/01-04)

Approved by DEMKO (File No.310107-01)

Approved by FIMKO (File No.15795)

■ Applications

- 1. Home appliances
- 2. OA equipment, FA equipment
- 3. SSRs

■ Model Line-up

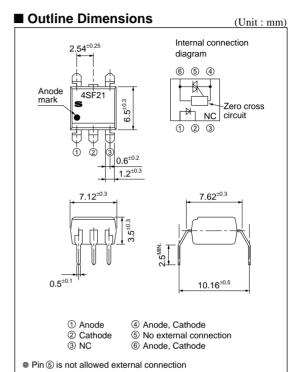
Minimum trigger current (I _{FT[MAX.]})	for AC 200V line		
7mA	PC4SF21YVZB		
5mA	PC4SF21YVZC		

■ Absolute Maximum Ratings (T_a=25°C)

Parameter		Symbol	Rating	Unit	
Input	*1 Forward current	I_F	50	mA	
	Reverse voltage	V_R	6	V	
Output	*1 RMS ON-state current	I _{T (rms)}	0.1	A	
	Peak one cycle surge current	I _{surge}	1.2 (50Hz sine wave)	A	
	Repetitive peak OFF-state voltage	V_{DRM}	800	V	
Operating temperature		T_{opr}	-30 to +100	°C	
Storage temperature		T _{stg}	-55 to +125	°C	
*2 Isolation voltage		V _{iso (rms)}	5.0	kV	
Soldering temperature		T_{sol}	260 (For 10s)	°C	

^{*1} The derating factors of absolute maximum ratings due to ambient temperature are shown in Fig.1, 2

V_{DRM}:800V Reinforced Insulation Type Phototriac Coupler for Triggering



^{*2 40} to 60% RH, AC for 1 minute, f=60Hz

■ Electro	o-optical Chara	cteristics					($T_a=25^{\circ}C)$
Parameter S			Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Innut	Forward voltage		V_F	$I_F=20mA$	_	1.2	1.4	V
Input	Reverse current		I_R	$V_R=3V$	_	-	10^{-5}	Α
Output	Repetitive peak OFF-state current		I_{DRM}	$V_D = V_{DRM}$			3×10 ⁻⁶	A
	ON-state voltage		V_{T}	$I_{T}=0.1A$	_	-	2.5	V
	Holding current		I_H	$V_D=4V$	0.1	-	3.5	mA
	Critical rate of rise of OFF-state voltage		dV/dt	$V_D=1/\sqrt{2} \cdot V_{DRM}$	500	1 000	-	V/µs
	Zero-cross voltage PC4SF21YVZB PC4SF21YVZC	N/	Resistance load, I _F =15mA			20	v	
		PC4SF21YVZC	V _{OX}	Resistance load, I _F =8mA	_	_	20	·
	Minimum trigger current PC4SF21YVZB PC4SF21YVZC	⊢ I _{rr}	V 4V D 1000	_	-	7	mA	
Transfer charac- teristics			$V_D=4V$, $R_L=100\Omega$	_	_	5	IIIA	
	Isolation resistance		R _{ISO}	DC=500V, 40 to 60%RH	5×10 ¹⁰	1011	_	Ω
	Turn-on time		t _{on}	$V_D=4V, R_L=100\Omega, I_F=20mA$	_	-	50	μs

Fig.1 RMS ON-state Current vs. Ambient **Temperature**

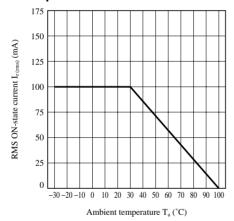


Fig.3 Forward Current vs. Forward Voltage

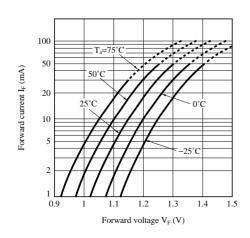


Fig.2 Forward Current vs. Ambient **Temperature**

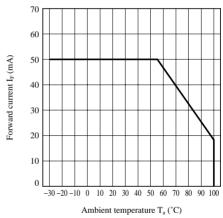


Fig.4 Minimum Trigger Current vs. Ambient **Temperature**

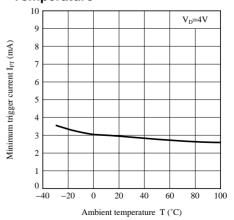


Fig.5 ON-state Voltage vs. Ambient Temperature

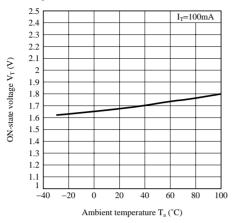


Fig.7 Repetitive Peak OFF-state Current vs. Ambient Temperature

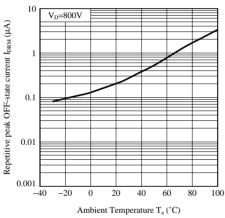


Fig.9 Turn-on Time vs. Forward Current

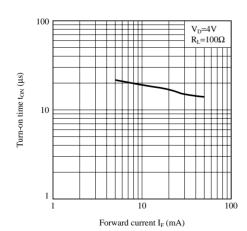


Fig.6 Holding Current vs. Ambient Temperature

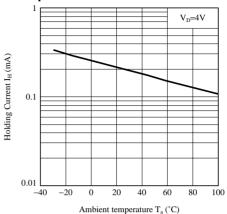


Fig.8 Relative Repetitive Peak OFF-state Voltage vs. Ambient Temperature

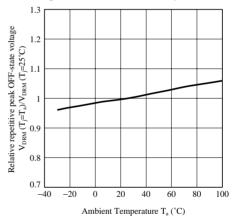


Fig.10 Zero-cross Voltage vs. Ambient Temperature (PC4SF21YVZB)

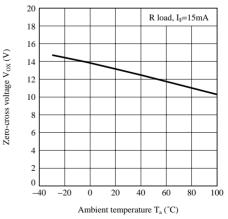
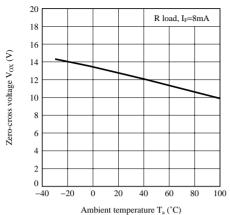


Fig.11 Zero-cross Voltage vs. Ambient Temperature (PC4SF21YVZC)



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